



INSULATION RELATED SPECIFICATIONS

		 7.62mm pitch TLPxxx type	 10.16mm pitch TLPxxxF type
Minimum Creepage Distance (*)	Cr	6.4mm	8.0mm
Minimum Clearance (*)	Cl	6.4mm	8.0mm
Minimum Insulation Thickness	ti	—	
Comperative Tracking Index (DIN IEC112/VDE0303, Part 1)	CTI	175 (VDE0110 Teil 2/01.89 Group III a)	

(*) in accordance with DIN VDE0110 Teil 2/01.89, Table 2, & 4

1. If a printed circuit is incorporated, the creepage distance and clearance may be reduced below this value (e. g. at a standard distance between soldering eye centres of 7.5mm). If this is not permissible, the user shall take suitable measures.
2. This photocoupler is suitable for 'safe electrical isolation' only within the safety limit data. Maintenance of the safety data shall be ensured by means of protective circuits.

VDE Test sign : Marking on product
for VDE0884



Marking on packing
for VDE0884



961001EBC2'

- Gallium arsenide (GaAs) is a substance used in the products described in this document. GaAs dust and fumes are toxic. Do not break, cut or pulverize the product, or use chemicals to dissolve them. When disposing of the products, follow the appropriate regulations. Do not dispose of the products with other industrial waste or with domestic garbage.
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Figure 1 Partial discharge measurement procedure according to VDE0884
Destructive test for qualification and sampling tests.

Method A
(for type and sampling tests, destructive tests)

t_1, t_2 = 1 to 10s
 t_3, t_4 = 1s
 t_p (Measuring time for partial discharge) = 50s
 t_b = 62s
 t_{ini} = 10s

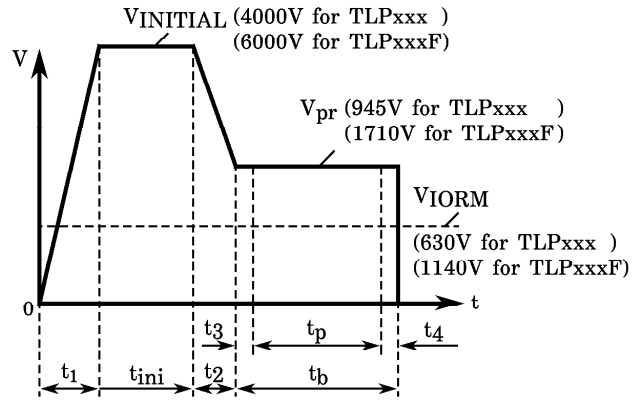


Figure 2 Partial discharge measurement procedure according to VDE0884
Non-destructive test for 100% inspection.

Method B
(for sample test, non-destructive test)

t_3, t_4 = 0.1s
 t_p (Measuring time for partial discharge) = 1s
 t_b = 1.2s

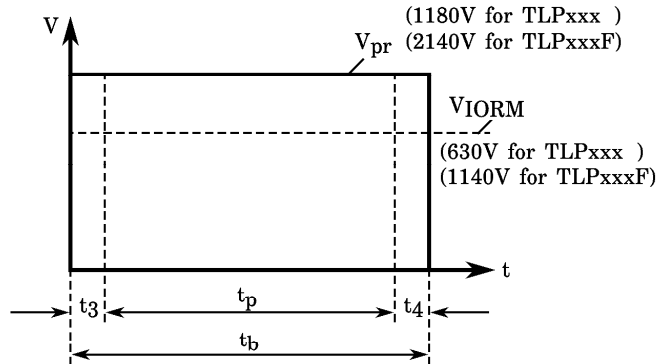


Figure 3 Dependency of maximum safety ratings on ambient temperature

